

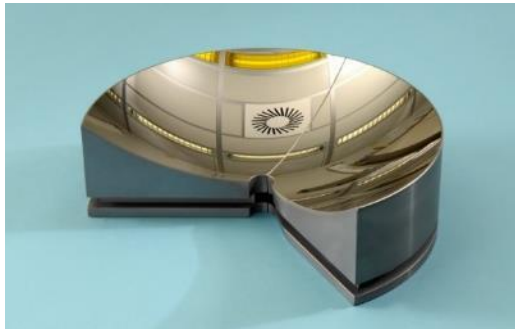
B-based ML coatings for Blue-X



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■ History

1997: Start of EUV multilayer development @ Fraunhofer IOF

2013: August 1st: Operations start @ **optiX fab.**

TODAY: Delivery of **14,258 EUV and X-ray mirrors** to customers

■ Mission

Fabrication of customized EUV optics and optical components for EUV lithography @ 13.5 nm, for EUV, soft and hard X-ray applications, synchrotron and FEL beamlines, metrology, R&D, HHG sources, etc.



Torsten Feigl



Marco Perske



Hagen Pauer



Tobias Fiedler



Philipp Naujok

ML coatings for short wavelengths

- main issues for ML coatings at shorter wavelengths ($\lambda < 13.5$ nm):



1st: lower reflectance

typical experimental values
for near normal incidence:

13.5 nm: $R \leq 70$ %

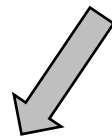
6.7 nm: $R \leq 65$ %

4.4 nm: $R \leq 15$ %

2.4 nm: $R \leq 20$ %

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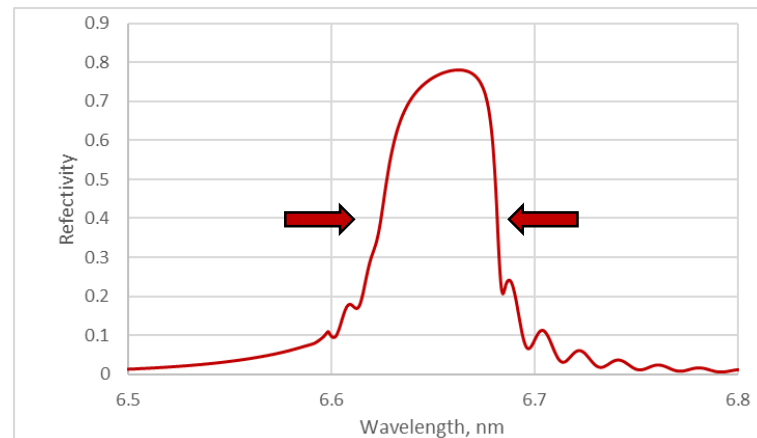
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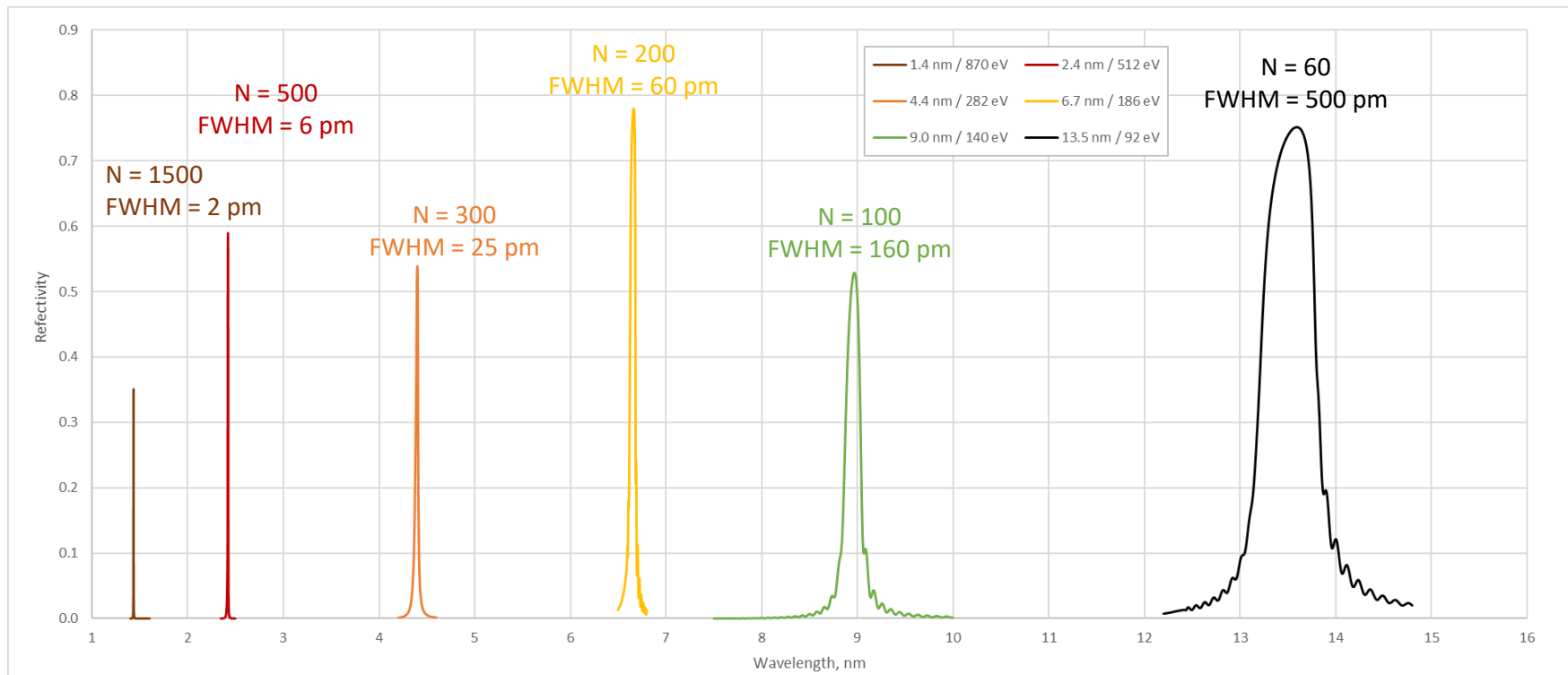


2nd: lower bandwidth



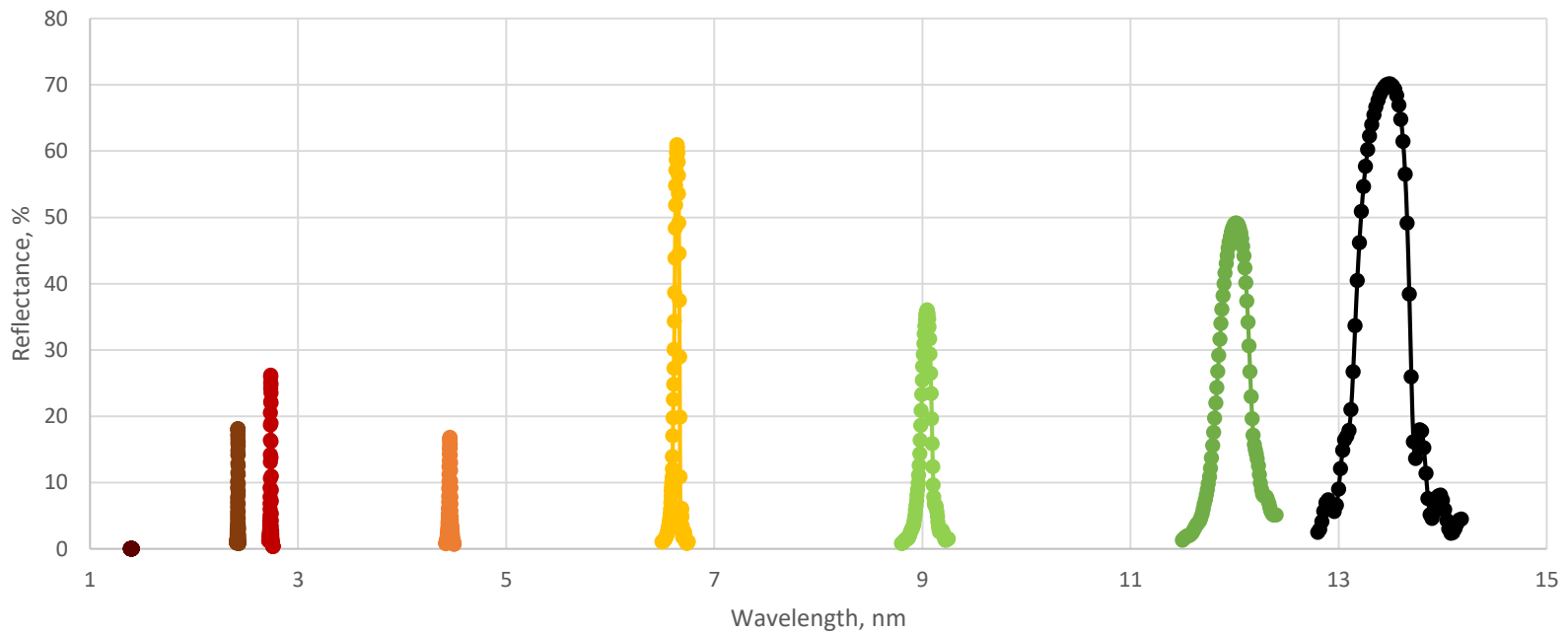
ML coatings for short wavelengths

- strongly decreasing bandwidth (FWHM) of the ML coating for shorter wavelengths
- reason: higher number of required contributing interfaces



ML coatings for short wavelengths

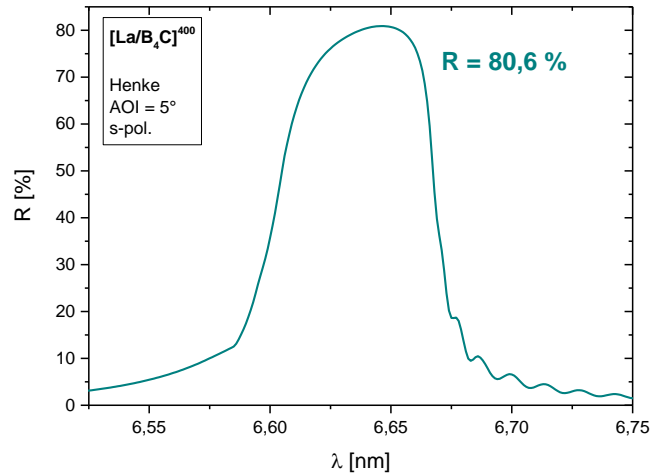
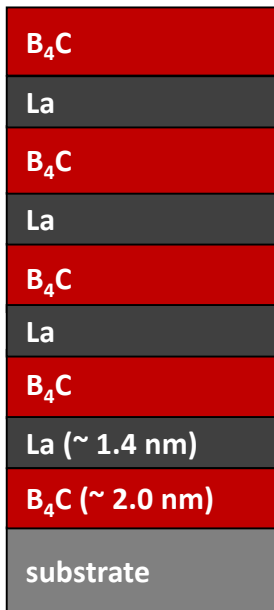
λ , nm	1.4	2.4	2.7	4.4	6.7	9.0	12.0	13.5
R, %	0.02	18.1	26.2	16.8	61.0	36.0	49.2	70.1
FWHM, nm	0.002	0.005	0.008	0.02	0.05	0.11	0.32	0.52



La/B₄C – simulation vs. experiment

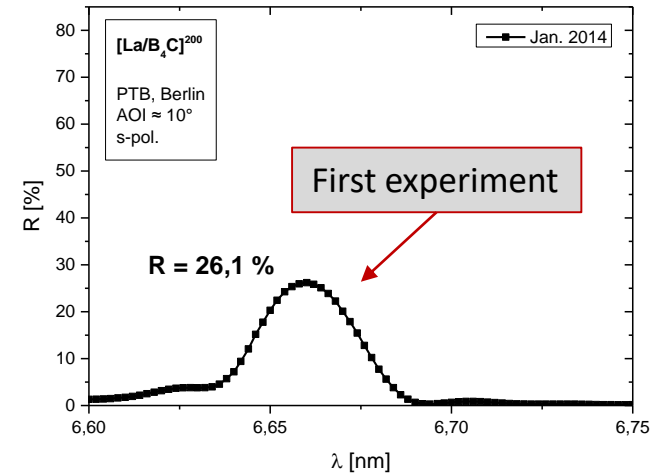
Simulation:

- > 250 bilayers of La and B₄C
- period thickness (La + B₄C): d = 3.4 nm
- ideal layers:



First experiments:

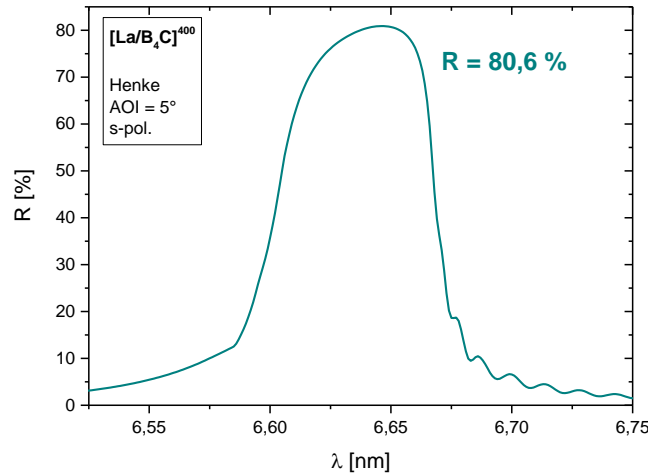
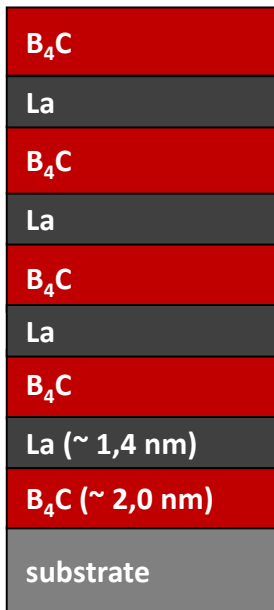
- very low reflectance
- huge difference between simulation and experiment



La/B₄C – simulation vs. experiment

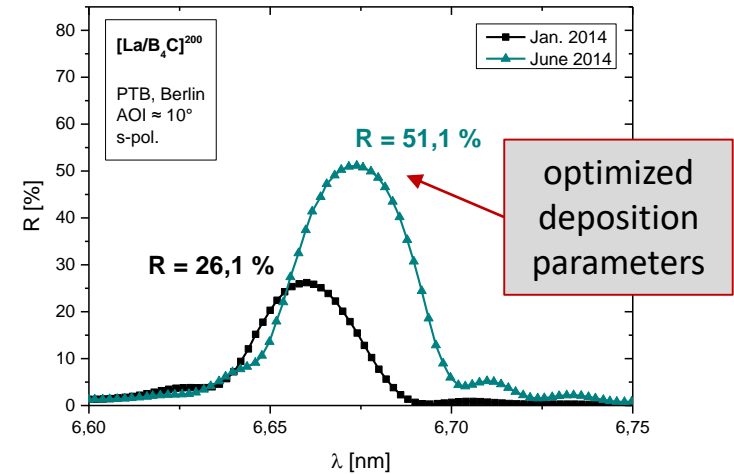
Simulation:

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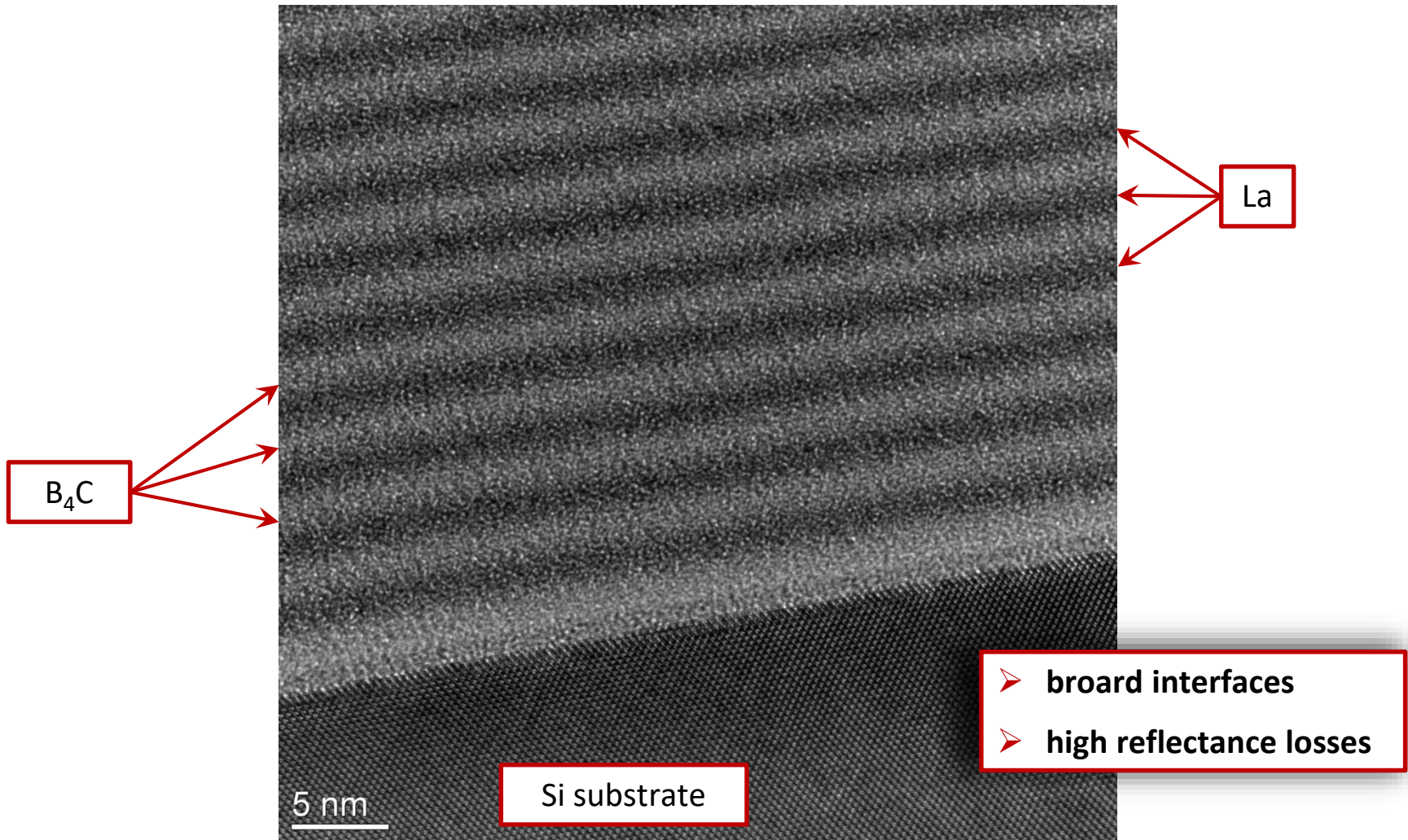
Optimized experiments:

- still low reflectance
- huge difference between simulation and experiment



➤ $R = 51,1\%$ @ 6,65 nm after optimizing all deposition parameters

HR-TEM of La/B₄C-ML

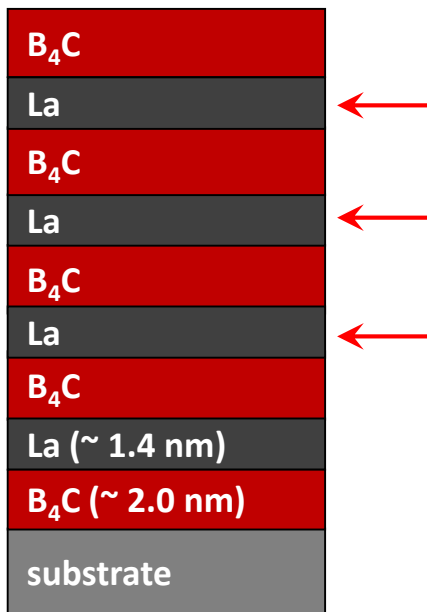


P. Naujok et al., Thin Solid Films 612, 414-418, 2016

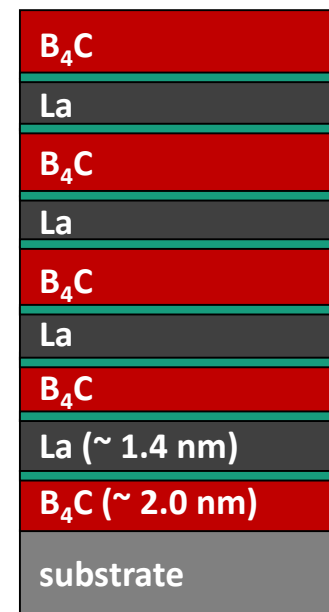
Reducing the interface width



1. Utilizing chemically stable materials



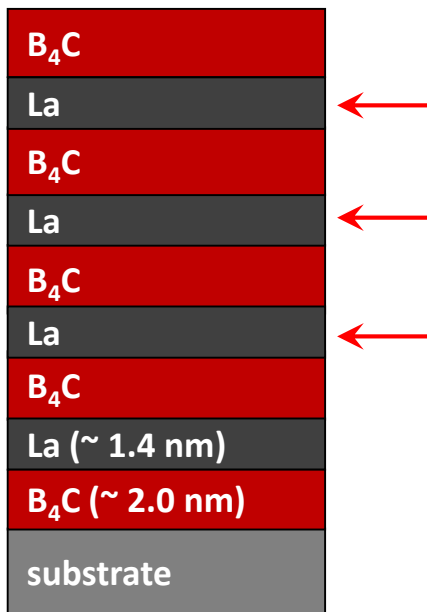
2. Application of barrier layers



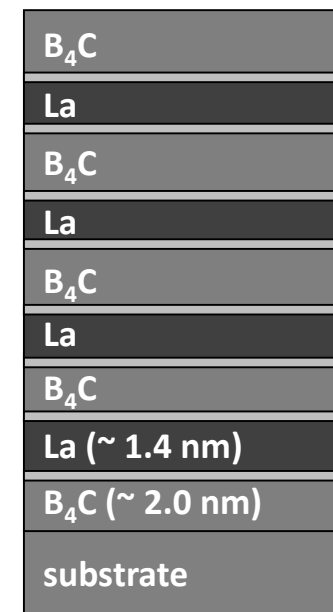
Reducing the interface width



1. Utilizing chemically stable materials



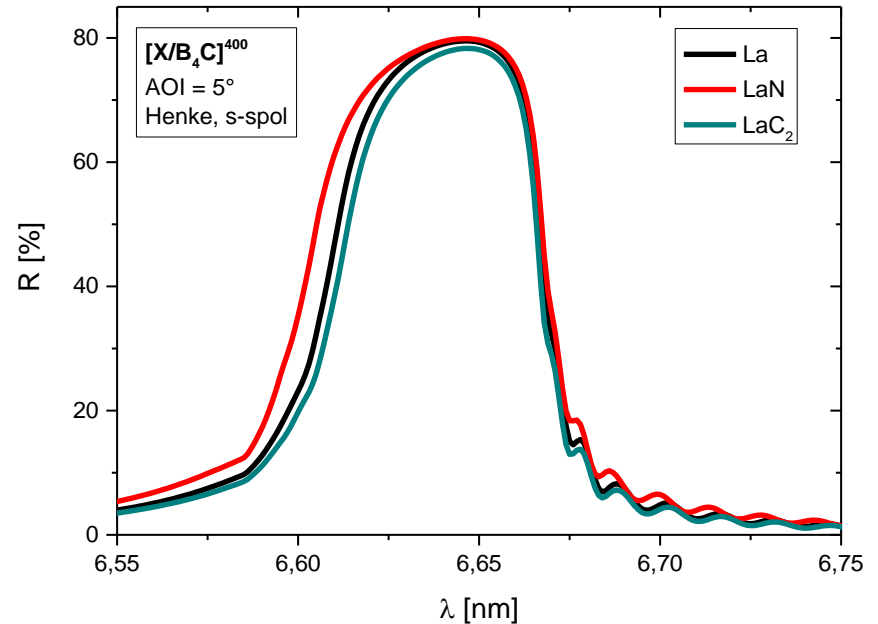
2. Application of barrier layers



1. Chemical passivation of La layers

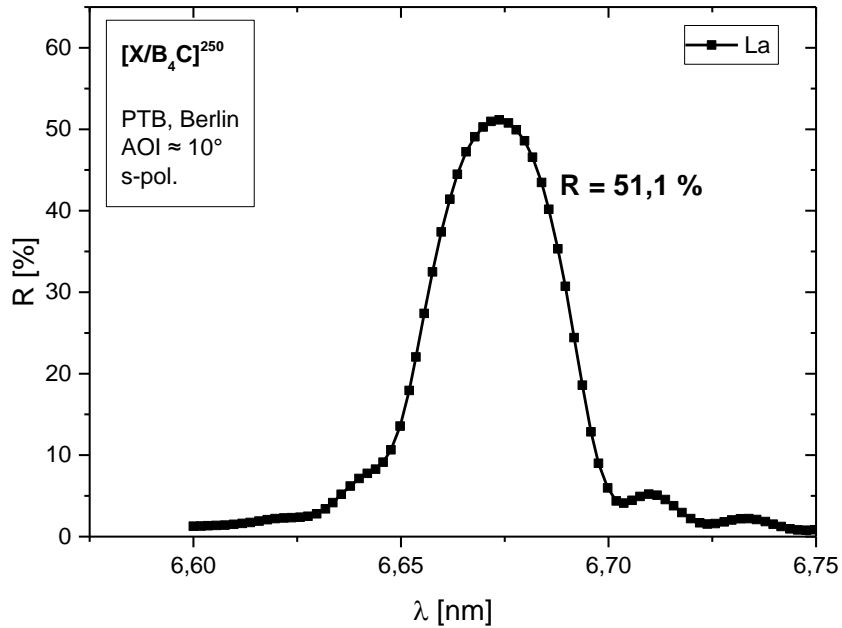
Theory:

- lowering chemical reactivity between B and La
- high peak reflectance achievable using La compounds
- expectation: higher experimental reflectance due to more narrow interfaces
- promising candidates:
 - LaN [1]
 - LaC₂



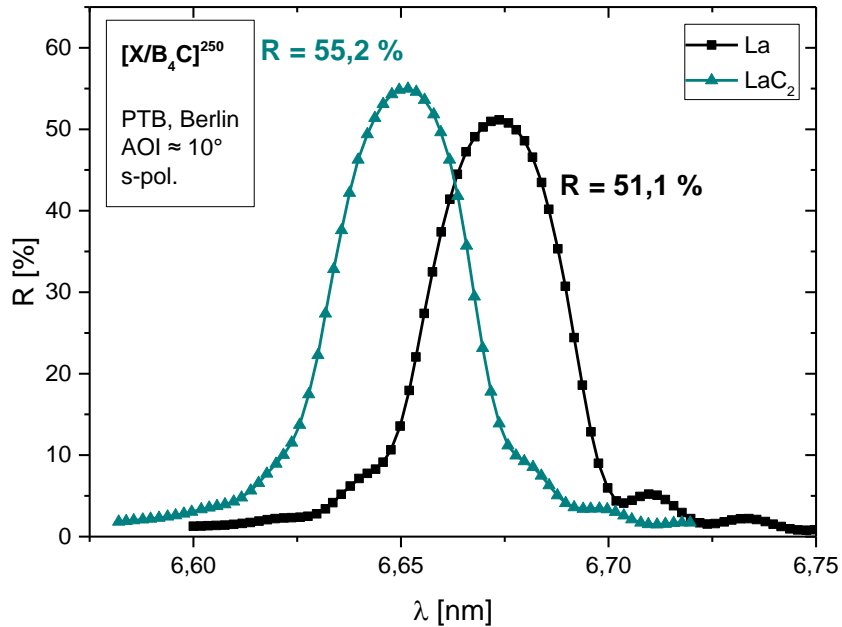
[1] T. Tsarfati et al., Thin Solid Films 518, 1365–1368 (2009)

1. Chemical passivation of La layers



System	EUVR @ 6,65 nm	
	R_{exp} [%]	$\Delta\lambda_{\text{exp}}$ [nm]
La/B ₄ C	51.1	0.036

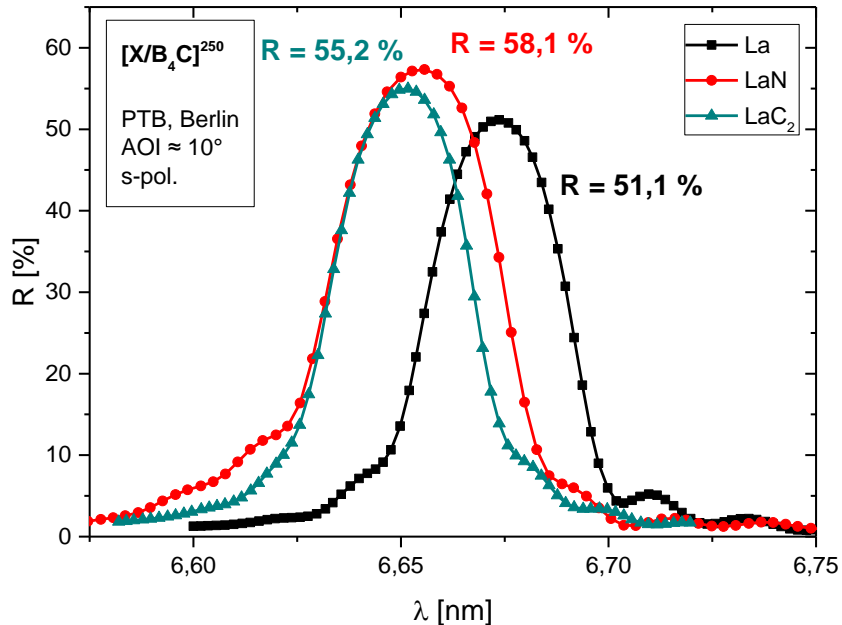
1. Chemical passivation of La layers



System	EUVR @ 6,65 nm	
	R_{exp} [%]	$\Delta\lambda_{\text{exp}}$ [nm]
La/ B_4C	51.1	0.036
LaC ₂ / B_4C	55.2	0.036

- increased reflectance due to less chemical reaction between La and B_4C
 - $R = 55,2 \%$ @ 6,65 nm (LaC₂)

1. Chemical passivation of La layers



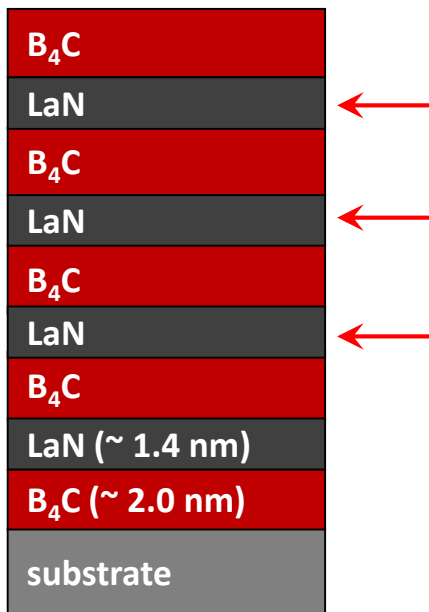
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La/B ₄ C	51.1	0.036
LaC ₂ /B ₄ C	55.2	0.036
LaN/B ₄ C	58.1	0.046

- increased reflectance due to less chemical reaction between La and B₄C
 - R = 55,2 % @ 6,65 nm (LaC₂)
 - R = 58,1 % @ 6,65 nm (LaN)

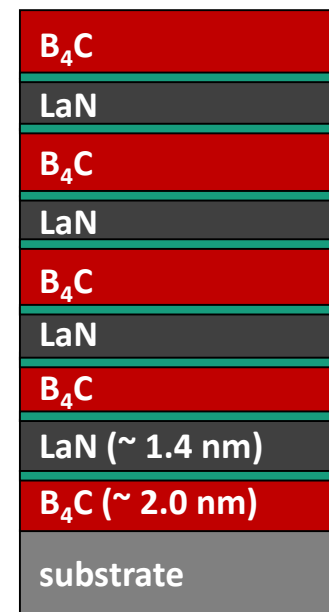
Reducing the interface width



1. Utilizing chemically stable materials → LaN ✓



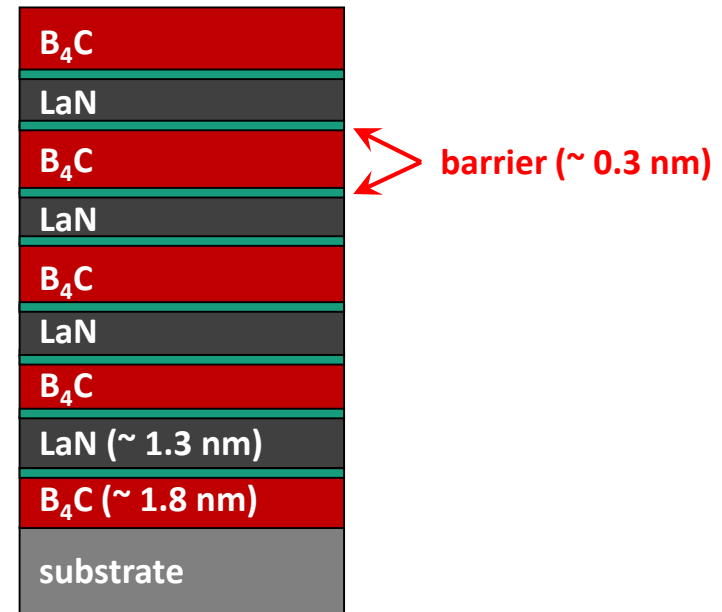
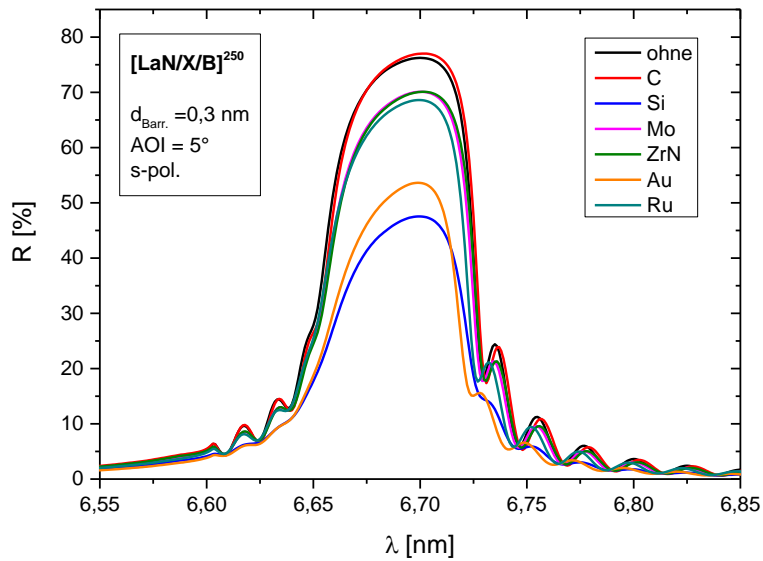
2. Application of barrier layers



2. Application of barrier layers

- barrier thickness 0.3 ... 0.5 nm
- important criteria:
 - optical properties
 - film growth
 - chemical reactivity with La, B, C, N

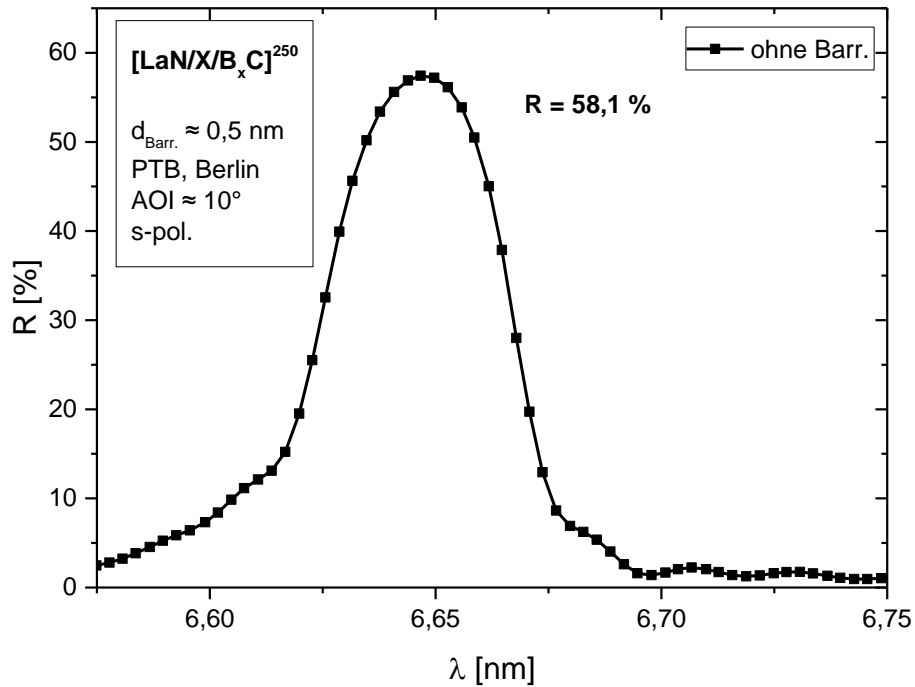
simulation for ideal layers:



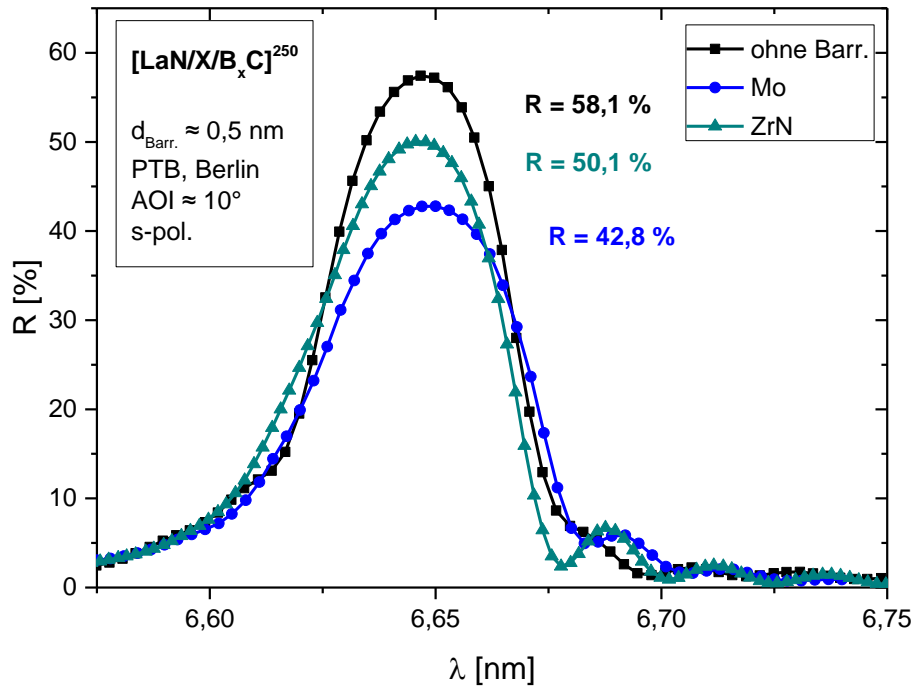
chosen candidates:

- C
- Mo
- ZrN

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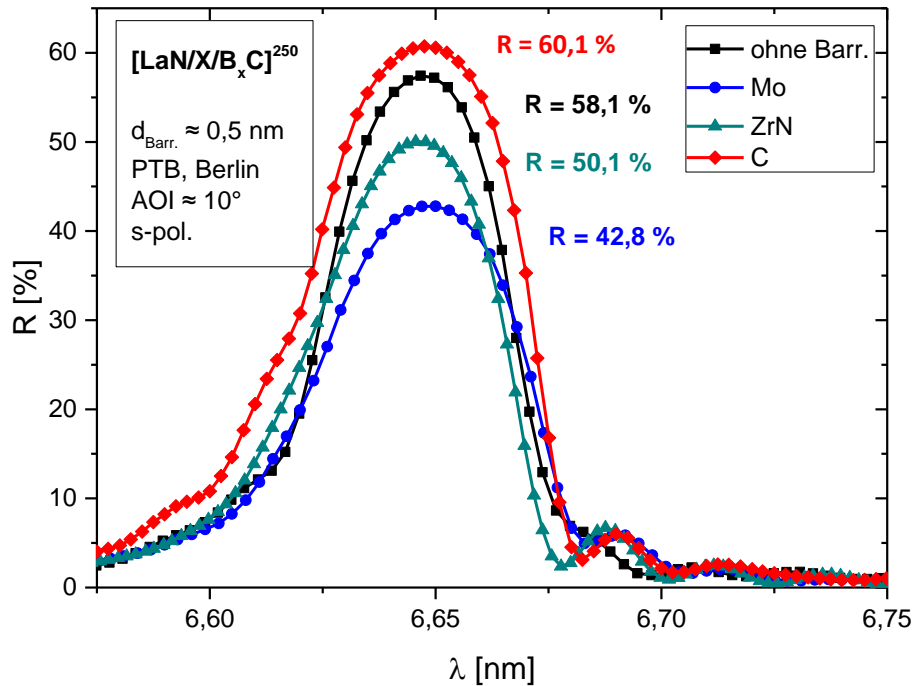


- **huge impact** on reflectance by extremely thin barriers
- no increased reflectance with

Mo ($\Delta R = - 15.3 \%$)

ZrN ($\Delta R = - 8.0 \%$)

2. Application of barrier layers



- **huge impact** on reflectance by extremely thin barriers
- no increased reflectance with
 - Mo ($\Delta R = -15.3 \%$)
 - ZrN ($\Delta R = -8.0 \%$)
- **increased** reflectance with C-barriers
 - C ($\Delta R = +2.0 \%$)

**Current best result
using C-barriers**

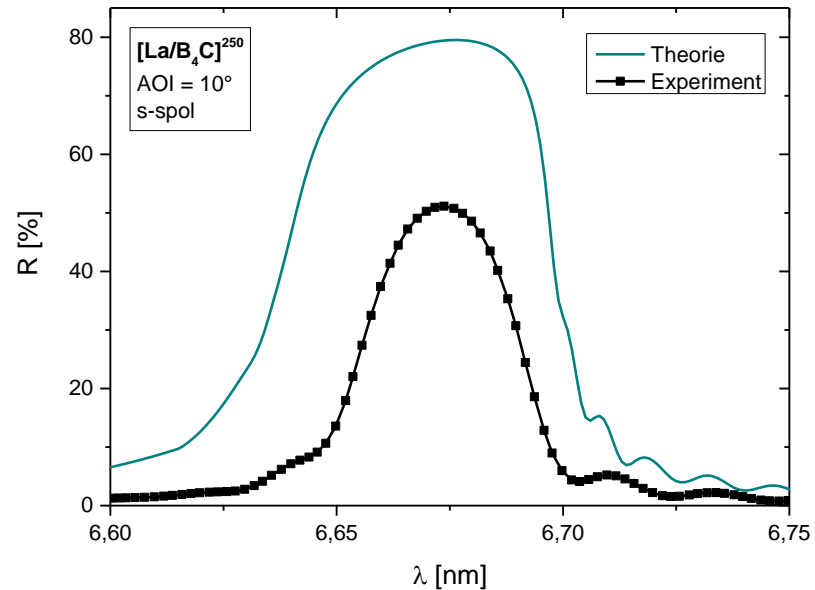
**$R = 60.1 \%$ @ $6,65 \text{ nm}$
(AOI = 10°)**

Summary

- huge difference between ideal and experimental reflectance at 6.7 nm wavelength
- reflection losses due to roughness, intermixing and chemical reactions at the interfaces

best results:

- La/B₄C: R = 51.1 %

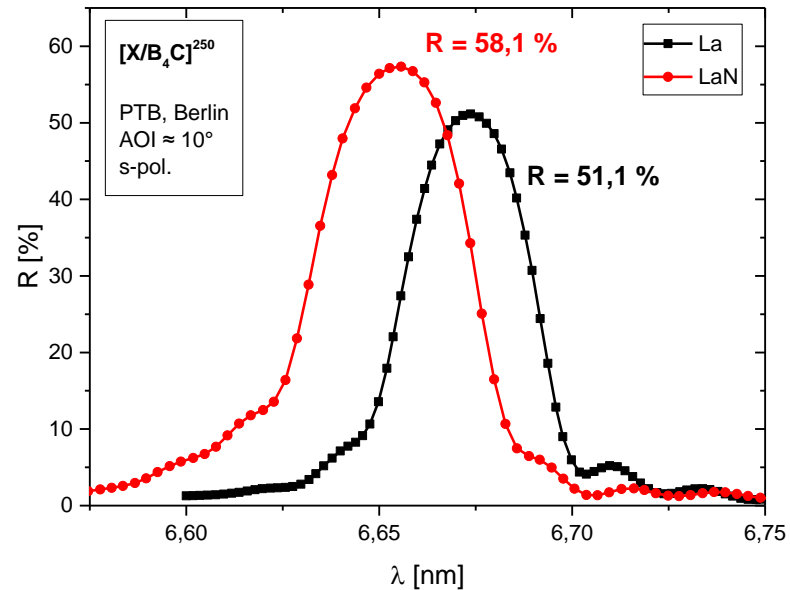


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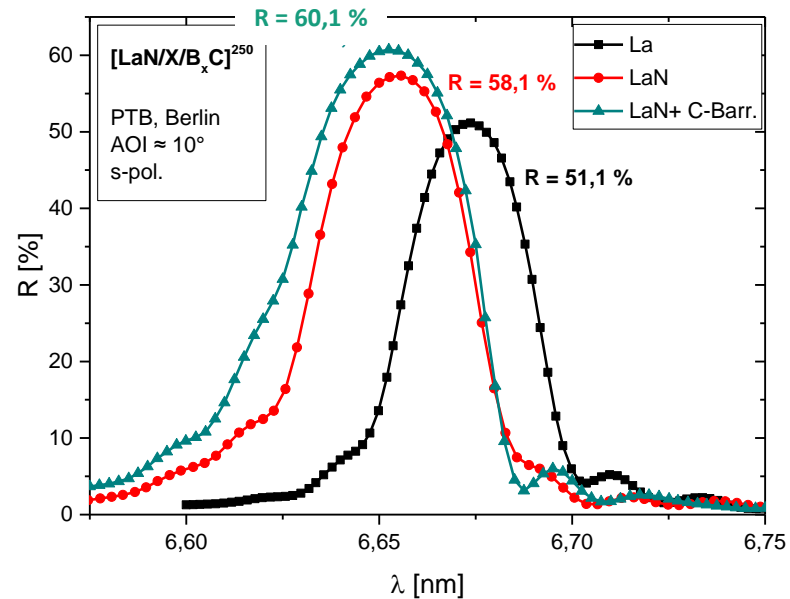


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- LaN/C/B₄C: R = 60.1 %

next steps:

- current championship data: R = 64.1 % using La/LaN/B [2]
- target for HVM: R > 70 %
- therefore: lower chemical reactivity, optimize barrier layers needed

[2] D. Kuznetsov et al., Optics Letters 40 (16) (2015)

Thank you.